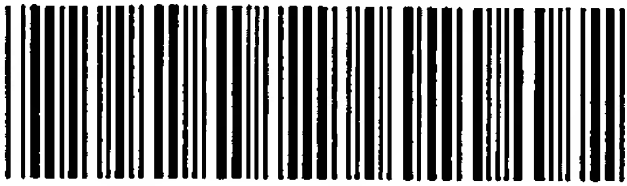


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/071,456	DICKERSON ET AL.	
	Examiner	Art Unit	
	Anh D. Mai	2814	

SEARCHED			
Class	Subclass	Date	Examiner
438	424	3/9/2005	A.M

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE (web): * shallow trench isolation and CMOS * shallow trench isolated CMOS	3/9/2005	A.M